

# GSMDS3710

## 30V N+P Dual Channel MOSFETs

### Product Description

These N+P dual Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

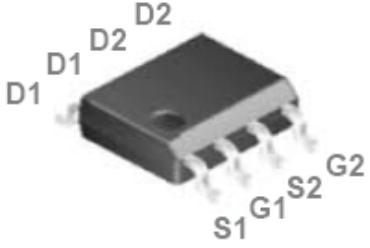
### Features

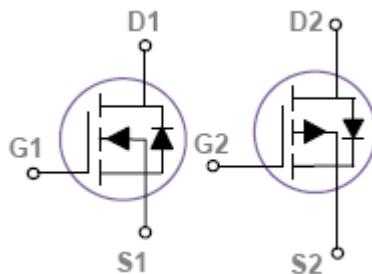
- N-Channel  
30V, 10A,  $R_{DS(ON)}=13m\Omega$ @ $V_{GS}=10V$
- P-Channel  
-30V, -6.5A,  $R_{DS(ON)}=28m\Omega$ @ $V_{GS}=-10V$
- Fast switching
- Suit for 4.5V / -4.5V Gate Drive Applications
- Green Device Available
- SOP-8 package design

### Applications

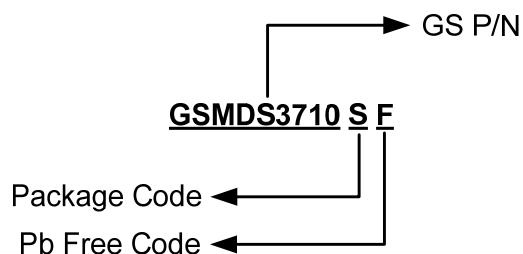
- DC Fan
- Motor Drive Applications
- Networking
- Half / Full Bridge Topology

### Packages & Pin Assignments

GSMDS3710SF (SOP-8)	
	Top View
Pin	Description
1	Source 1
2	Gate 1
3	Source 2
4	Gate 2
5	Drain 2
6	Drain 2
7	Drain 1
8	Drain 1

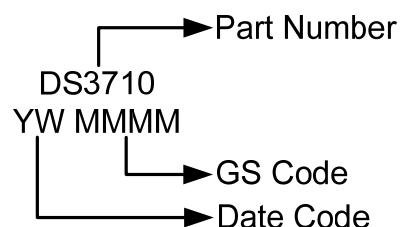


## Ordering Information



Part Number	Package	Quantity Reel
GSMDS3710SF	SOP-8	4000 PCS

## Marking Information



## Absolute Maximum Ratings

T<sub>C</sub>=25°C Unless otherwise noted

Symbol	Parameter	Typical		Unit
		N-Channel	P-Channel	
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> =25°C	10	A
		T <sub>C</sub> =100°C	6.3	
I <sub>DM</sub>	Pulsed Drain Current (Note 1)	36	-26	A
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> =25°C	5	W
		Derate above 25°C	0.04	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to +150		°C
T <sub>STG</sub>	Storage Temperature Range	-55 to +150		°C
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient	62.5		°C/W
R <sub>θJC</sub>	Thermal Resistance-Junction to Case	25		°C/W

Note 1: Repetitive Rating: Pulsed width limited by maximum junction temperature.

## Electrical Characteristics (N-Channel)

$T_J=25^\circ\text{C}$  Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	30			V
$\Delta BV_{\text{DSS}}/\Delta T_J$	$BV_{\text{DSS}}$ Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$		0.03		$\text{V}/^\circ\text{C}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	1.6	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient			-4		$\text{mV}/^\circ\text{C}$
$I_{GSS}$	Gate Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$			1	
		$V_{DS}=24\text{V}, V_{GS}=0\text{V}, T_J=125^\circ\text{C}$			10	uA
$I_S$	Continuous Source Current	$V_G=V_D=0\text{V}$ , Force Current			10	A
$I_{SM}$	Pulsed Source Current				20	
$R_{DS(\text{on})}$	Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=8\text{A}$			13	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=4\text{A}$			18	
$g_{FS}$	Forward Transconductance	$V_{DS}=10\text{V}, I_D=3\text{A}$		6		S
$V_{SD}$	Diode Forward Voltage	$V_{GS}=0\text{V}, I_S=1\text{A}$			1	V
<b>Dynamic</b>						
$Q_g$	Total Gate Charge (Note 2,3)	$V_{DS}=15\text{V}, V_{GS}=4.5\text{V}, I_D=5\text{A}$		7.4	12	
$Q_{gs}$	Gate-Source Charge (Note 2,3)			2.3	5	nC
$Q_{gd}$	Gate-Drain Charge (Note 2,3)			3	6	
$C_{iss}$	Input Capacitance	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$		620	900	
$C_{oss}$	Output Capacitance			85	125	pF
$C_{rss}$	Reverse Transfer Capacitance			60	90	
$t_{d(on)}$	Turn-On Time (Note 2,3)	$V_{DD}=15\text{V}, I_D=1\text{A}, V_{GS}=10\text{V}, R_G=6\Omega$		3.8	7	
$t_r$				10	19	ns
$t_{d(off)}$	Turn-Off Time (Note 2,3)			22	42	
$t_f$				6.6	13	
$R_g$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.8	5.6	$\Omega$

Note 2: The data tested by pulsed, pulse width  $\leq 300\text{us}$ , duty cycle  $\leq 2\%$ .

Note 3: Essentially independent of operating temperature.

## Electrical Characteristics (P-Channel)

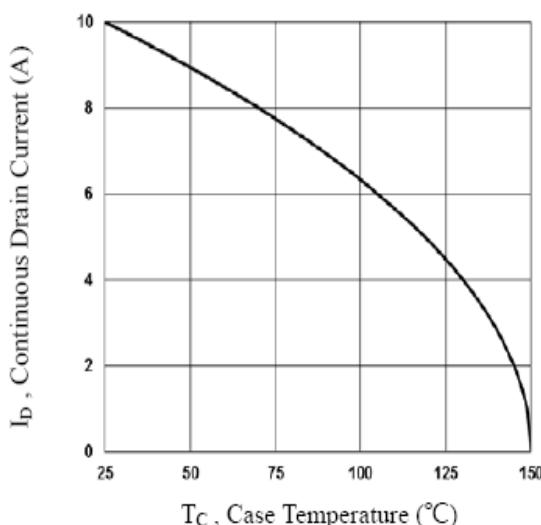
$T_J=25^\circ\text{C}$  Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=-250\mu\text{A}$	-30			V
$\Delta BV_{\text{DSS}}/\Delta T_J$	$BV_{\text{DSS}}$ Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=-1\text{mA}$		-0.03		$\text{V}/^\circ\text{C}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1	-1.6	-2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient			4		$\text{mV}/^\circ\text{C}$
$I_{GSS}$	Gate Leakage Current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$			-1	
		$V_{DS}=-24\text{V}, V_{GS}=0\text{V}, T_J=125^\circ\text{C}$			-10	uA
$I_S$	Continuous Source Current	$V_G=V_D=0\text{V}, \text{Force Current}$			-6.5	A
$I_{SM}$	Pulsed Source Current				-13	
$R_{DS(\text{on})}$	Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-6\text{A}$			28	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-4\text{A}$			42	
$g_{FS}$	Forward Transconductance	$V_{DS}=-10\text{V}, I_D=-3\text{A}$		9		S
$V_{SD}$	Diode Forward Voltage	$V_{GS}=0\text{V}, I_S=-1\text{A}$			-1	V
<b>Dynamic</b>						
$Q_g$	Total Gate Charge (Note 2,3)	$V_{DS}=-15\text{V}, V_{GS}=-4.5\text{V}, I_D=-5\text{A}$		8	15	nC
$Q_{gs}$	Gate-Source Charge (Note 2,3)			3.3	6	
$Q_{gd}$	Gate-Drain Charge (Note 2,3)			2.3	5	
$C_{iss}$	Input Capacitance	$V_{DS}=-15\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$		757	1280	pF
$C_{oss}$	Output Capacitance			122	210	
$C_{rss}$	Reverse Transfer Capacitance			88	175	
$t_{d(on)}$	Turn-On Time (Note 2,3)	$V_{DD}=-15\text{V}, I_D=-1\text{A}, V_{GS}=-10\text{V}, R_G=6\Omega$		4.6	9	ns
$t_r$				14	26	
$t_{d(off)}$	Turn-Off Time (Note 2,3)			34	58	
$t_f$				18	35	
$R_g$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.8	5.6	$\Omega$

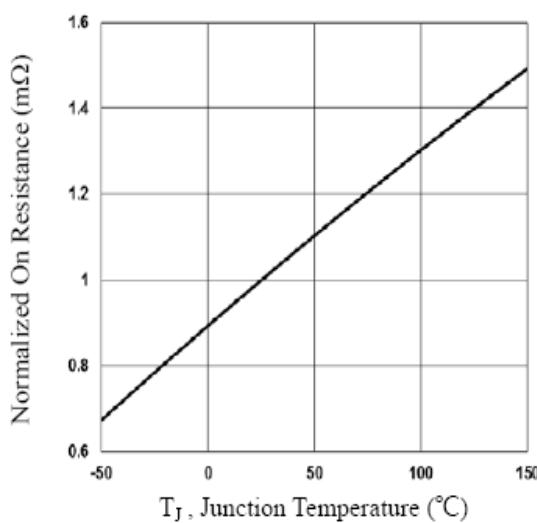
Note 2: The data tested by pulsed, pulse width  $\leq 300\text{us}$ , duty cycle  $\leq 2\%$ .

Note 3: Essentially independent of operating temperature.

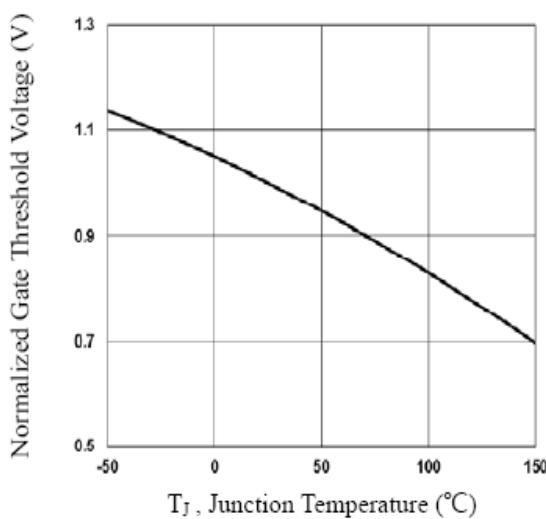
## Typical Performance Characteristics (N-Channel)



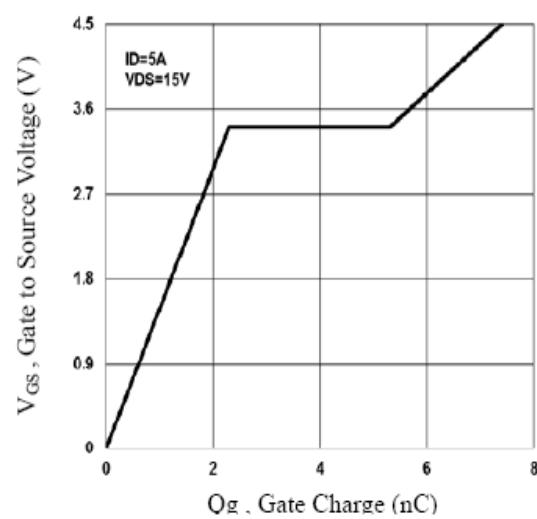
**Fig.1 Continuous Drain Current vs.  $T_c$**



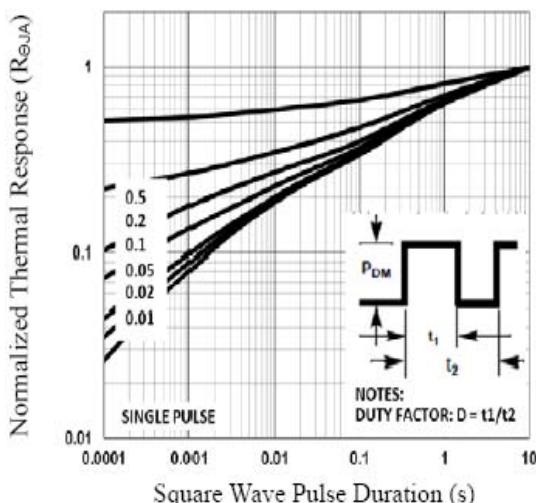
**Fig.2 Normalized RDS(on) vs.  $T_j$**



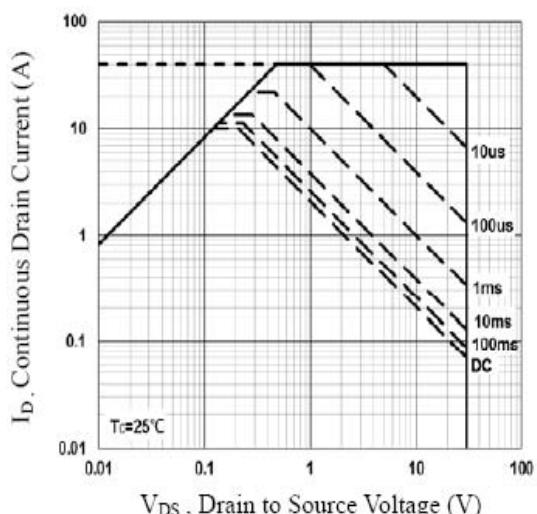
**Fig.3 Normalized  $V_{th}$  vs.  $T_j$**



**Fig.4 Gate Charge Waveform**



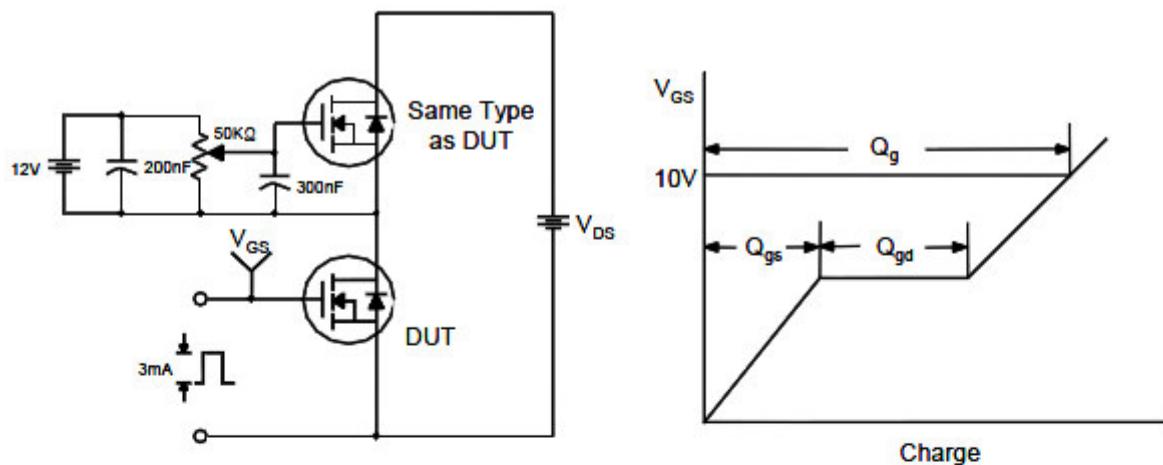
**Fig.5 Normalized Transient Response**



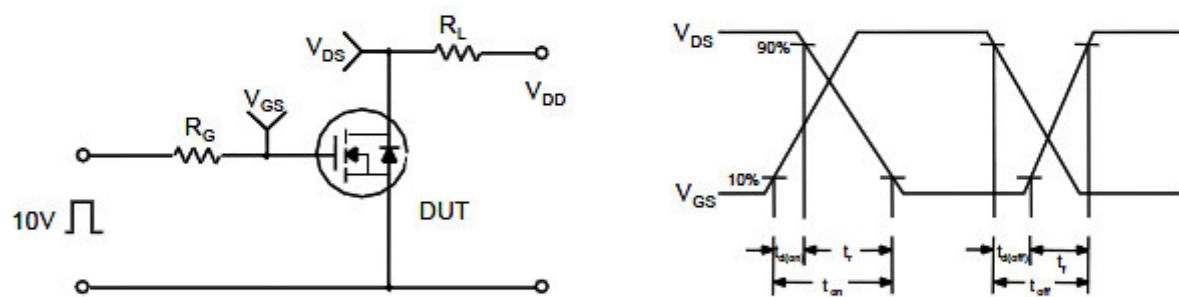
**Fig.6 Maximum Safe Operation Area**

## Typical Performance Characteristics (N-Channel)

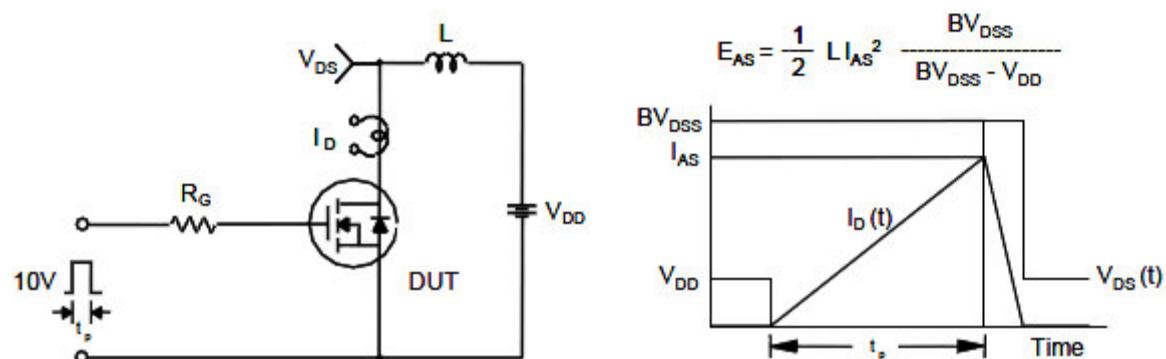
Gate Charge Test Circuit & Waveform



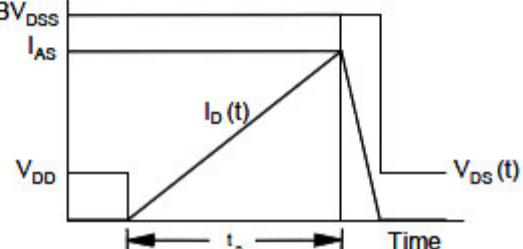
Resistive Switching Test Circuit & Waveforms



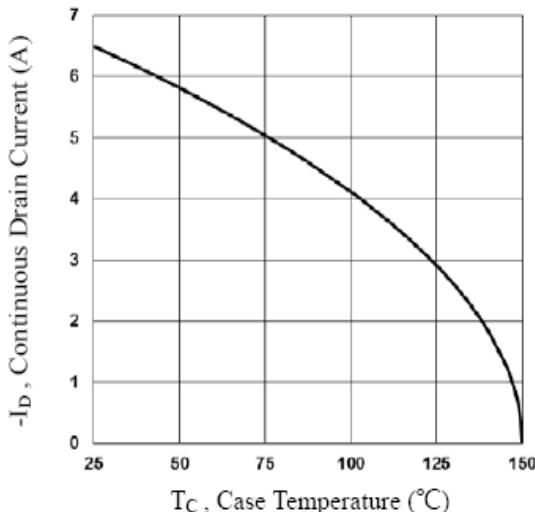
Unclamped Inductive Switching Test Circuit & Waveforms



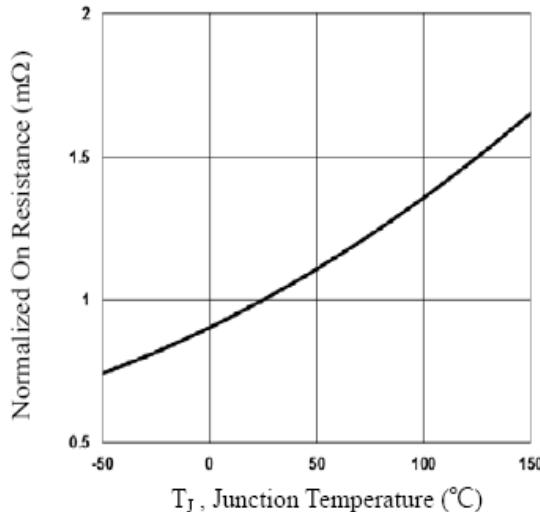
$$E_{AS} = \frac{1}{2} L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$



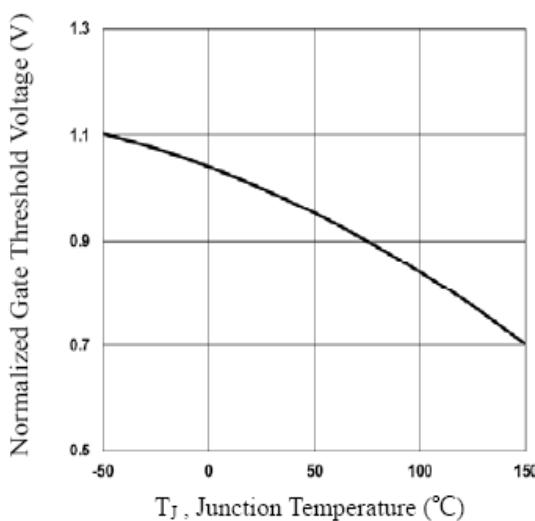
## Typical Performance Characteristics (P-Channel)



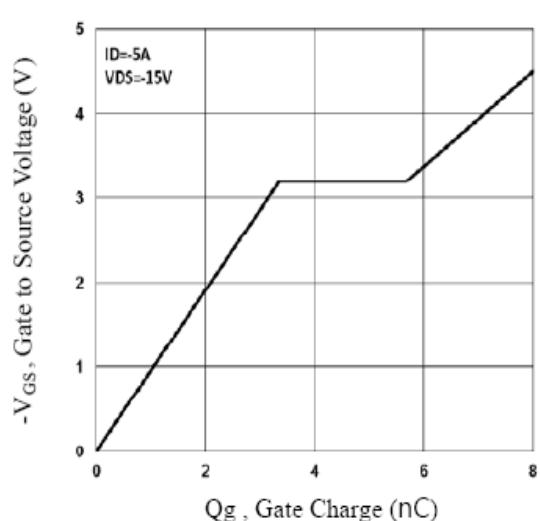
**Fig.1 Continuous Drain Current vs.  $T_c$**



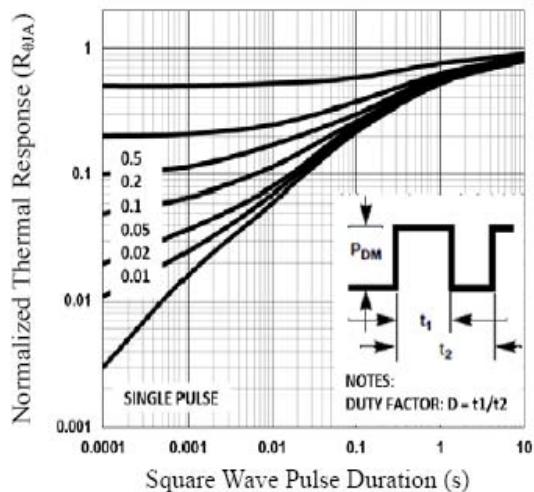
**Fig.2 Normalized RD<sub>SON</sub> vs.  $T_j$**



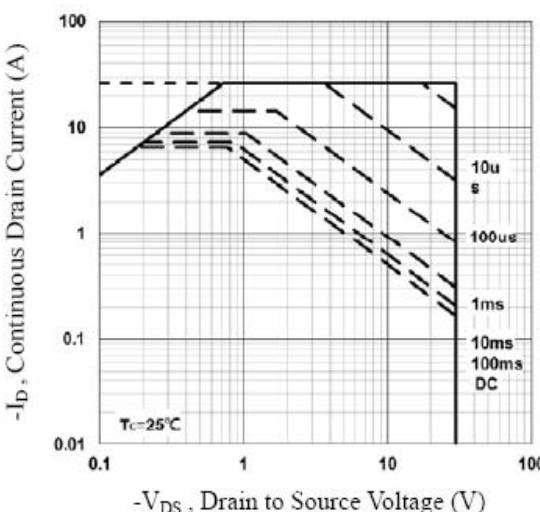
**Fig.3 Normalized  $V_{th}$  vs.  $T_j$**



**Fig.4 Gate Charge Waveform**



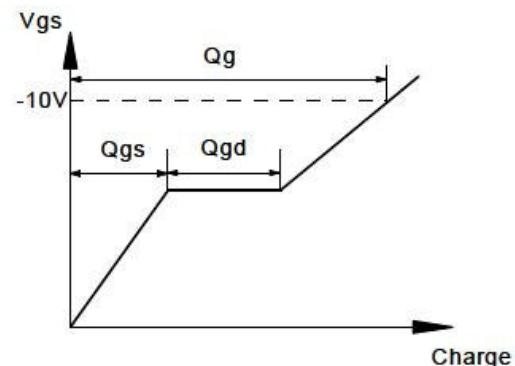
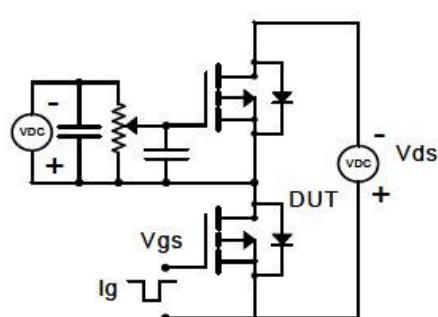
**Fig.5 Normalized Transient Impedance**



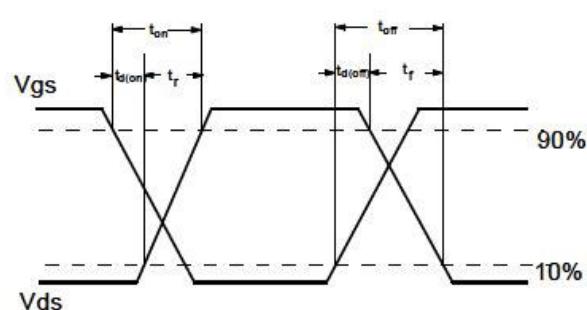
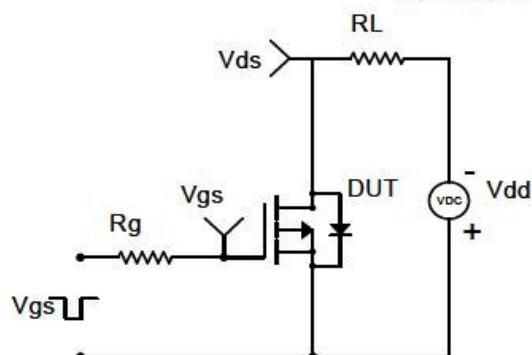
**Fig.6 Maximum Safe Operation Area**

## Typical Performance Characteristics (P-Channel)

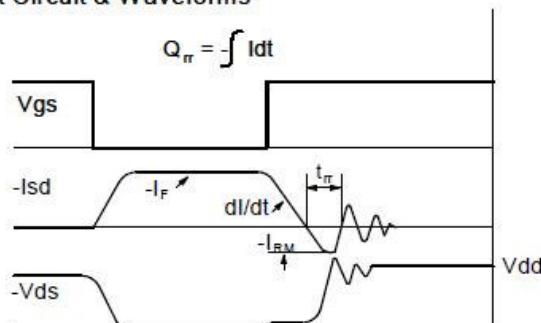
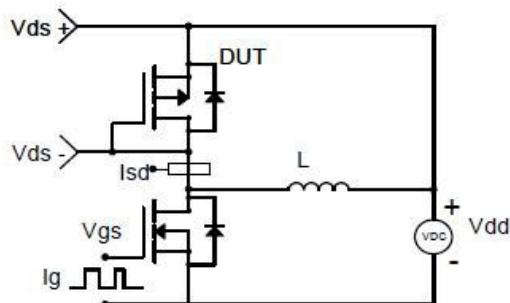
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

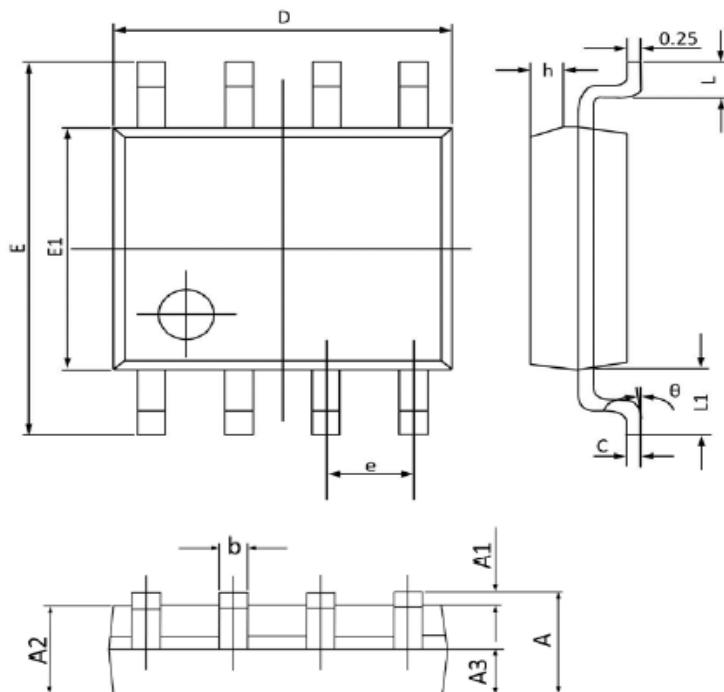


Diode Recovery Test Circuit & Waveforms



## Package Dimension

### SOP-8



### Dimensions

Symbol	Millimeters		Inches	
	Min	Max	Min	Max
<b>A</b>	1.350	1.750	0.053	0.068
<b>A1</b>	0.100	0.250	0.004	0.009
<b>A2</b>	1.300	1.500	0.052	0.059
<b>A3</b>	0.600	0.700	0.024	0.027
<b>b</b>	0.390	0.480	0.016	0.018
<b>c</b>	0.210	0.260	0.009	0.010
<b>D</b>	4.700	5.100	0.186	0.200
<b>E</b>	5.800	6.200	0.229	0.244
<b>E1</b>	3.700	4.100	0.146	0.161
<b>e</b>	1.270 (BSC)		0.050 (BSC)	
<b>h</b>	0.250	0.500	0.010	0.019
<b>L</b>	0.500	0.800	0.019	0.031
<b>L1</b>	1.050 (BSC)		0.041 (BSC)	
<b>θ</b>	0 °	8 °	0 °	8 °

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